

**Search Notes**

Application/Control No.

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Examiner

CHAN S. PARK

Applicant(s)/Patent under  
Reexamination

YANO ET AL.

Art Unit

2625

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.15, 1.13	4/10/2007	CP
348	207.2	4/10/2007	CP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	4/10/2007	CP
Inventor search	4/10/2007	CP